In the Specification:

Please replace page 3 of the International application with the new text, as follows:

during the testing procedure. Thus, increased requirements are demanded for the contacting block. The contacting block serves external signal input to the contact areas of the drive circuit or to the contact areas of the data lines or gate lines or the corresponding shorting bars.

The above mentioned problems of the prior art are solved by inventive apparatus according to claims 1, 13, 20 and 28 as well as the inventive method according to claims 21 and 27.

According to an aspect of the invention, the object is solved by a drive electronics for driving an optoelectronic device with a matrix of picture elements. The drive electronics has a drive circuit with input terminals and output terminals. Further to this, the drive electronics includes a first arrangement of contact areas connected with the drive circuit and a second arrangement of contact areas connected with the drive circuit. Preferably, both arrangements of contact areas are connected with the input terminals of the drive circuit.

Furthermore, the first arrangement of contact areas has first contact areas and the second arrangement of contact areas has second contact areas. Preferably, the second contact areas of the second arrangement of contact areas are larger than the first contact areas of the first arrangement of contact areas

The present invention allows to generate a test pattern which is sufficiently complex for the purpose of testing via the second arrangement of contact areas. For testing purposes, no arbitrary pictures have to be generated but patterns which are less complex compared to normal operation. Therefore, the number of contact areas for generating a test pattern can be reduced compared to the number of contact areas for generating an arbitrary picture during normal operation. This reduction of the number

contact areas allows that the contact areas can be enlarged. Thus, it is possible to test display elements in a reliable, quicker and more effective fashion.

The drive electronics is preferably designed so that the number of input terminals of the drive circuit, by which the arrangement of contact areas for testing the drive circuit is